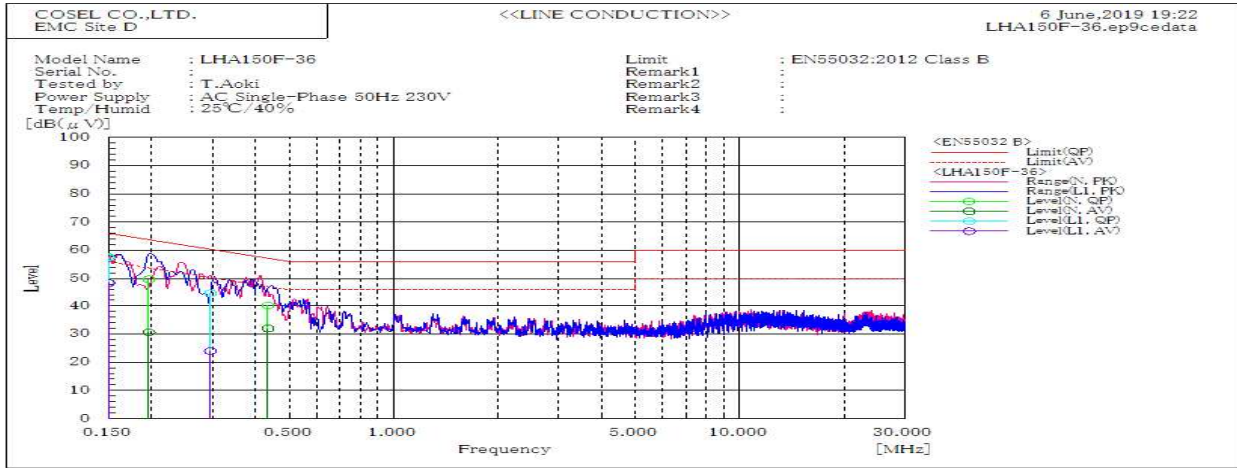
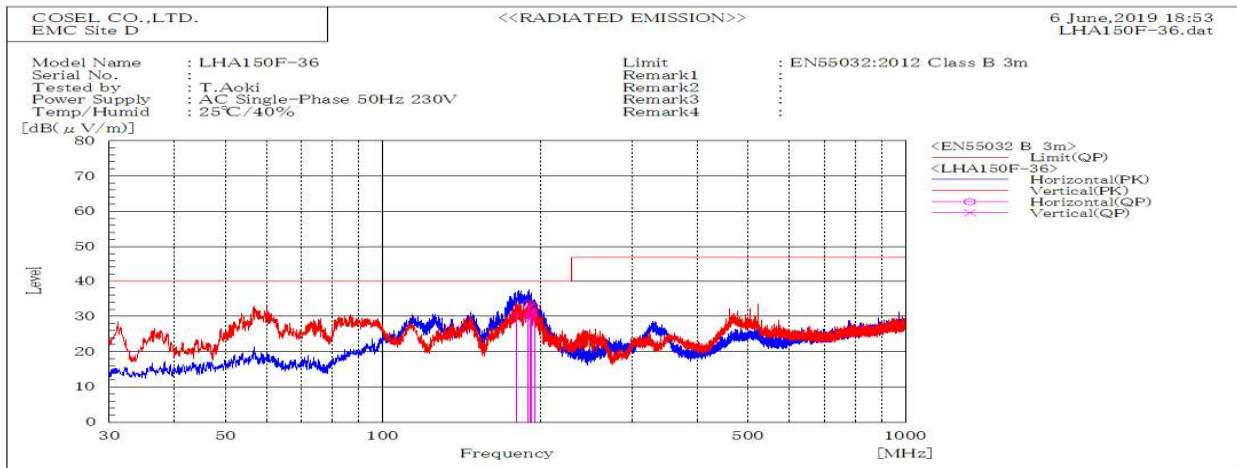


DATA SHEET		Date	12-Sep-19
Model	LHA150F-36	Temp.	25 degreeC
Test	EMI Line conduction & Radiated emission	Humid.	40 %RH
		Tested by	T.Aoki



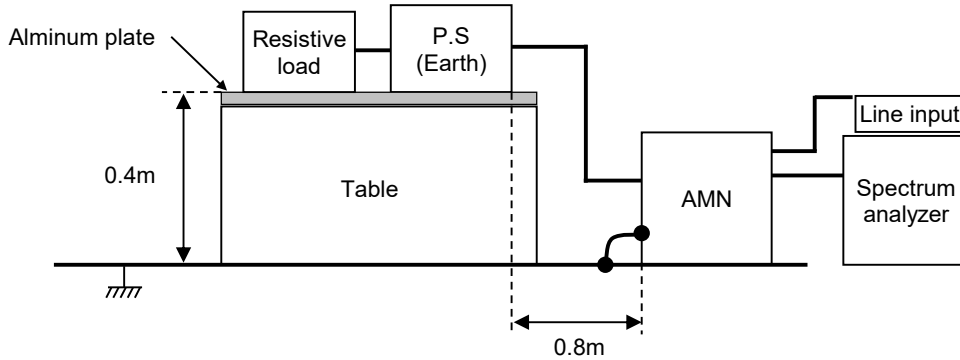
Frequency MHz	Line	Level dB(μV)		Limit dB(μV)		Margin dB		Pass/Fail	Remark
		QP	AV	QP	AV	QP	AV		
0.15	L1	57.4	48.5	66	56	8.6	7.5	Pass	
0.15	L1	57.4	48.4	66	56	8.6	7.6	Pass	
0.296	L1	44.8	23.9	60.4	50.4	15.6	26.5	Pass	
0.15	N	57.5	48.5	66	56	8.5	7.5	Pass	
0.15	N	57.6	48.5	66	56	8.4	7.5	Pass	
0.434	N	40.2	31.9	57.2	47.2	17	15.3	Pass	
0.196	N	49.7	30.6	63.8	53.8	14.1	23.2	Pass	



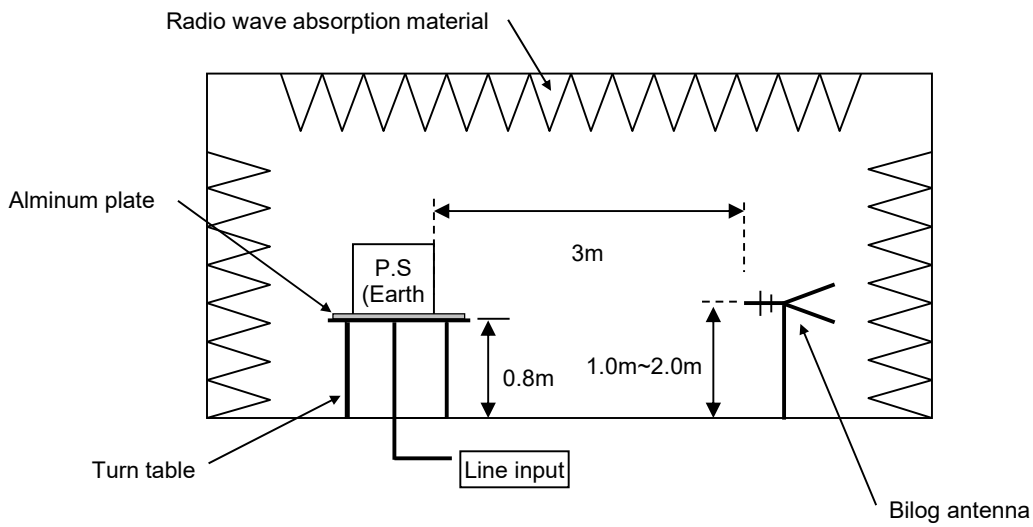
Frequency MHz	Polarization	Stability	Level dB(μV/m)	Limit dB(μV/m)	Margin dB	Pass/Fail	Height cm	Angle deg	Remark
			QP	QP	QP				
180.5	V	Stable	30.6	40	9.4	Pass	100	123.4	
189.794	V	Stable	29.6	40	10.4	Pass	100	191.6	
190.013	H	Stable	33.6	40	6.4	Pass	200	9.3	
192.167	V	Stable	31.7	40	8.3	Pass	100	148.9	
191.843	H	Stable	30.2	40	9.8	Pass	200	0	
195.095	H	Stable	32.4	40	7.6	Pass	200	158.3	

DATA SHEET		Date	12-Sep-19
Model	Circuit used for measurement	Temp.	25 degreeC
Test	EMI Line conduction & Radiated emission	Humid.	40 %RH
		Tested by	T.Aoki

1. Line conduction



2. Radiated emission

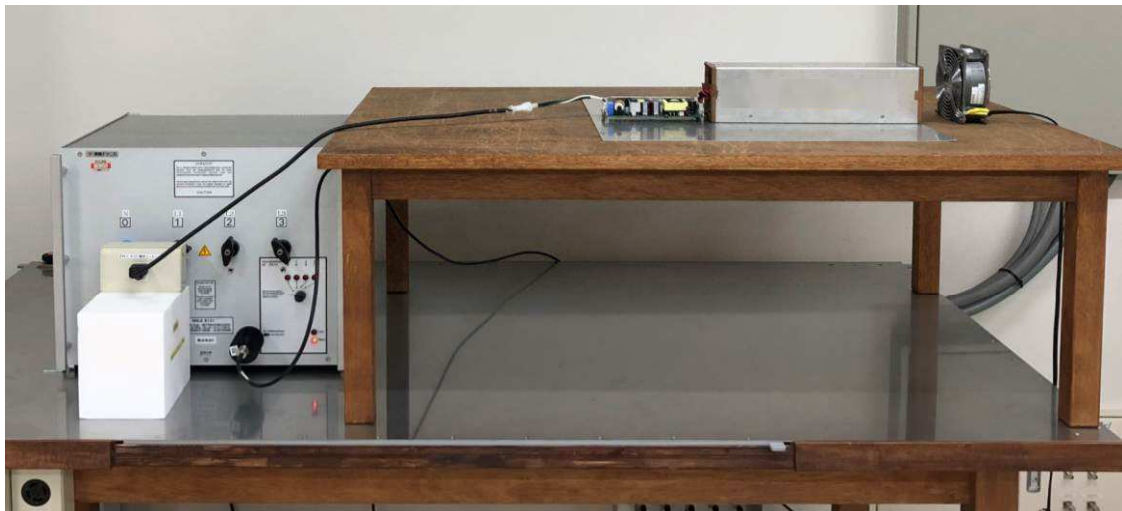


Conditions

Test : EMI
 Model Name : LHA150F-36

Photographs of test set-up

1.LINE CONDUCTION



2.RADIATED EMISSION

